

**Search Notes**

Application/Control No.

10/767,767

Examiner

Thomas D. Lee

Applicant(s)/Patent and/or  
Reexamination

OGAWA, HIDEHIKO

Art Unit

2625

**SEARCHED**

| Class   | Subclass          | Date       | Examiner |
|---------|-------------------|------------|----------|
| 358     | 1.15, 402,<br>440 | 11/22/2005 | TDL      |
| 379     | 100.01            | 11/22/2005 | TDL      |
| 379     | 100.08            | 11/22/2005 | TDL      |
| 379     | 100.13            | 11/22/2005 | TDL      |
| 379     | 100.17            | 11/22/2005 | TDL      |
|         |                   |            |          |
| updated |                   | 5/9/2006   | TDL      |
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**INTERFERENCE SEARCHED**

| Class                           | Subclass | Date     | Examiner |
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| Interference Search<br>Printout |          | 5/9/2006 | TDL      |

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

|  | DATE | EXMR |
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